

80V N-Channel Split Gate MOSFET

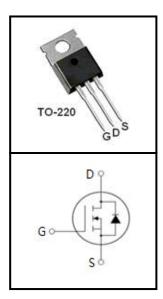
FEATURES

- Trench Power MOSFET Technology
- Low RDS(ON)
- Low Gate Charge
- Optimized For Fast-switching Applications

APPLICATIONS

- ●DC/DC Converter
- Ideal for high-frequency switching and synchronous rectification





Device Marking and Package Information					
Device	Package	Marking			
CSP08N6P5	TO-220	CSP08N6P5			

Absolute Maximum Ratings at T _j = 25°C unless otherwise noted							
Parameter		Symbol	Value	Unit			
Drain-Source Voltage (V _{GS} = 0V)		V_{DSS}	80	V			
Continuous Drain Current T _C = 25°C	(note1)		130	Α			
Continuous Drain Current T _C = 100°C	(note1)	I _D	100	A			
Pulsed Drain Current	(note2)	I _{DM}	280	Α			
Gate Source Voltage		V _{GSS}	±20	V			
Single Pulse Avalanche Energy	(note3)	E _{AS}	100	mJ			
Power Dissipation T _C = 25°C	(note4)	P_{D}	56	W			
Operating Junction and Storage Temperatur	e Range	T _J , T _{stg}	-55~+175	°C			

Thermal Characteristics						
Parameter	Symbol	Value	Unit			
Thermal Resistance, Junction-to-Case	$R_{\theta JC}$	0.4	°C/W			
Thermal Resistance, Junction-to-Ambient	$R_{\theta JA}$	62.5	-0/00			



Electrical Characteristics T _j = 25°C unless otherwise specified									
Parameter	Symbol	Test Conditions		Unit					
Farameter	Syllibol	rest Conditions	Min.	Тур.	Max.	Oilit			
Static									
Drain-Source Breakdown Voltage	$V_{(BR)DSS}$	$V_{GS} = 0V, I_{D} = 250\mu A$	80			V			
Zero Gate Voltage Drain Current	I _{DSS}	$V_{DS} = 64V, V_{GS} = 0V, T_{J} = 25^{\circ}C$			1	uA			
2010 Gate Voltage Brain Garrent	פטי	$V_{DS} = 64V, V_{GS} = 0V, T_{J} = 100^{\circ}C$			5	uA			
Gate-Source Leakage	I_{GSS}	V_{GS} = $\pm 20V$			±100	nA			
Gate-Source Threshold Voltage	$V_{GS(th)}$	$V_{DS} = V_{GS}$, $I_D = 250 \mu A$	1.2		2.5	V			
Drain-Source On-Resistance (note2)	R _{DS(on)}	$V_{GS} = 10V, I_{D} = 30A$		4.5	6.5	mΩ			
Diam-Source On-Nesistance (notez)	DS(on)	$V_{GS} = 4.5V, I_{D} = 20A$		6.5	8.5	mΩ			
		Dynamic							
Input Capacitance	C_{iss}	V _{GS} = 0V,		2900					
Output Capacitance	C _{oss}	$V_{GS} - UV$, $V_{DS} = 40V$, f = 1.0MHz		420		pF			
Reverse Transfer Capacitance	C_{rss}			40					
Total Gate Charge (4.5V)	Q_g			40					
Gate-Source Charge	Q_gs	V _{DS} = 40V, I _D = 15A, V _{GS} = 10V		7.2		nC			
Gate-Drain Charge	Q_{gd}			6.5					
Turn-on Delay Time	t _{d(on)}			8.3					
Turn-on Rise Time	t _r	V _{DS} = 40V, I _D = 15A		4.2		- ns			
Turn-off Delay Time	$t_{\text{d(off)}}$	$R_{G} = 3\Omega$		36					
Turn-off Fall Time	t _f			6.9					
	В	ody Diode Characteristics							
Source-Drain Current(Body Diode)	I _S				130	Α			
Pulsed Source-Drain Current(Body Diode)	I _{SDM}				280				
Body Diode Voltage	V_{SD}	$T_J = 25^{\circ}C$, $I_{SD} = 1A$, $V_{GS} = 0V$			1.2	V			
Reverse Recovery Time	t _{rr}	TJ=25°C I _F =15A,		27		nS			
Reverse Recovery Charge	Q _{rr}	di/dt=100A/µs		89		nc			

Notes

- 1. The data tested by surface mounted on a 1 inch2 FR-4 board with 2OZ copper.
- 2. The data tested by pulsed , pulse width $\leqq\!300\text{us}$, duty cycle $\leqq\!2\%$
- 3. The EAS data shows Max. rating . The test condition is VDD =25V,VGS =10V,L=0.1mH $\,$
- 4. The power dissipation is limited by 175°C junction temperature
- 5. The data is theoretically the same as ID and IDM , in real applications , should be limited by total power dissipation.



Typical Characteristics $T_J = 25^{\circ}C$, unless otherwise noted

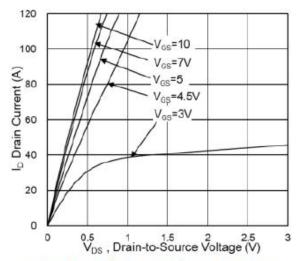


Fig.1 Typical Output Characteristics

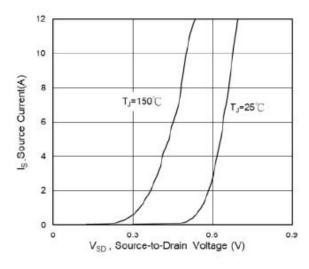


Fig.3 Source Drain Forward Characteristics

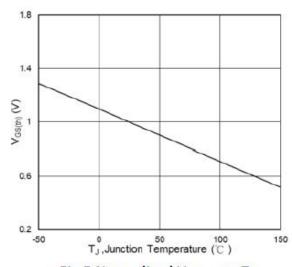


Fig.5 Normalized V_{GS(th)} vs. T_J

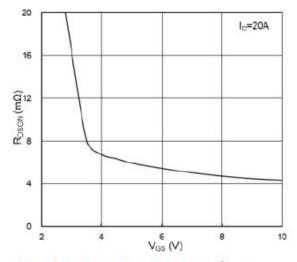


Fig.2 On-Resistance vs. G-S Voltage

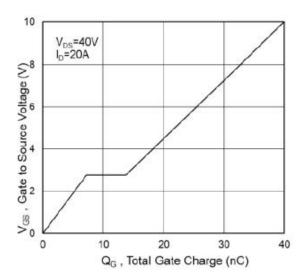


Fig.4 Gate-Charge Characteristics

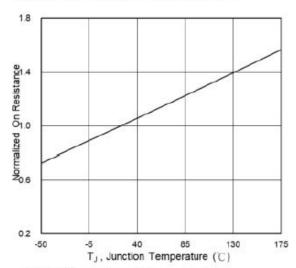
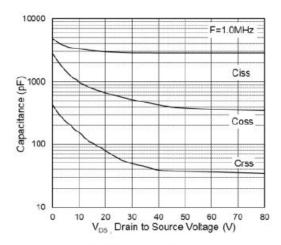


Fig.6 Normalized RDSON vs. TJ



Typical Characteristics $T_J = 25^{\circ}C$, unless otherwise noted



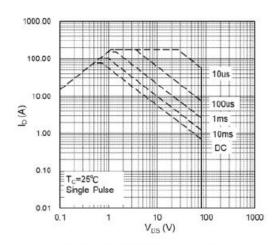


Fig.7 Capacitance

Fig.8 Safe Operating Area

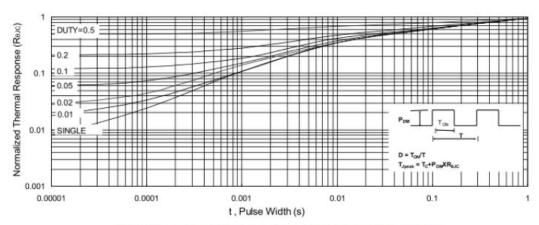


Fig.9 Normalized Maximum Transient Thermal Impedance



Figure A: Gate Charge Test Circuit and Waveform

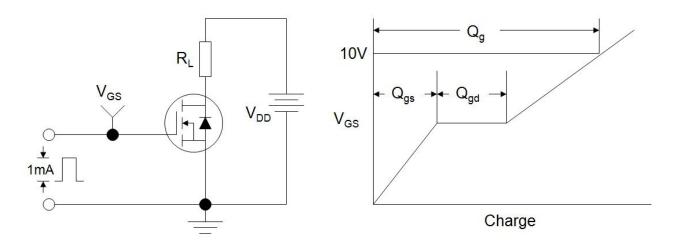


Figure B: Resistive Switching Test Circuit and Waveform

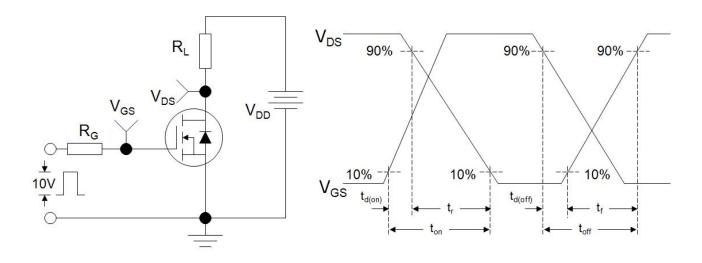
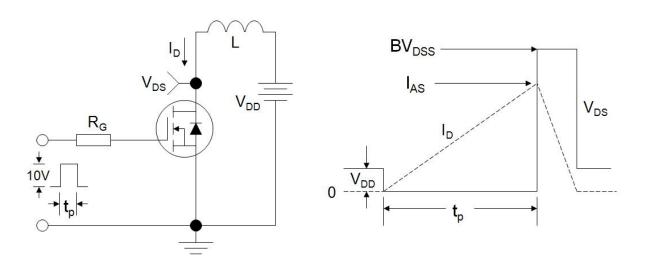
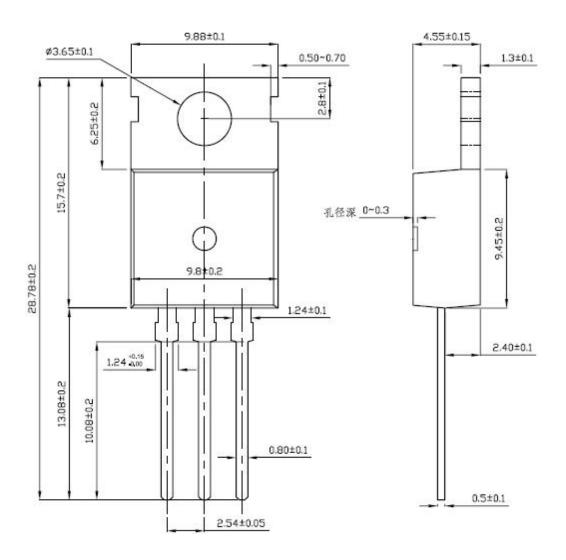


Figure C: Unclamped Inductive Switching Test Circuit and Waveform





TO-220



DIM	Millimeters Inc		hes	DIM	Millimeters		Inches			
DIM	Min. Max. Min. Max.	DIIVI	Min.	Max.	Min.	Max.				
Α	4.400	4.600	0.173	0.181	е	2.540*		0.100*		
A1	2.250	2.550	0.089	0.100	e1	4.980	5.180	0.196	0.204	
b	0.710	0.910	0.028	0.036	F	2.650	2.950	0.104	0.116	
b1	1.170	1.370	0.046	0.054	Н	7.900	8.100	0.311	0.319	
С	0.330	0.650	0.013	0.026	h	0.000	0.300	0.000	0.012	
c1	1.200	1.400	0.047	0.055	L	12.900	13.400	0.508	0.528	
D	9.910	10.250	0.390	0.404	L1	2.850	3.250	0.112	0.128	
E	8.950	9.750	0.352	0.384	V	7.500 REF		0.295	0.295 REF	
E1	12.650	12.950	0.498	0.510	Φ	3.600	3.800	0.142	0.150	



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